

AMENDMENTS TO THE CLAIMS

1. (Original) A method of testing a memory die, comprising:

allowing said memory die to be placed in a location outside of a production facility of said die;

testing said memory die while said die is in said location; and

storing a partial memory cell address on said die as a result of said testing act, wherein said address corresponds to a memory cell having failed said testing act.
2. (Original) The method in claim 1, wherein said testing act comprises testing said die while said die is part of an electronic system.
3. (Original) The method in claim 2, wherein said testing act comprises testing said die while said electronic system is in a power management mode.
4. (Original) The method in claim 2, wherein said testing act comprises testing said die while said die is part of a computer system.
5. (Original) The method in claim 2, wherein said testing act comprises testing said die while said die is part of a telephone system.

Application No. 10/022,436
Amendment dated March 19, 2006
Reply to Office Action of July 28, 2005 January 18, 2006

Docket No.: M4065.0559/P559-B

6. (Original) The method in claim 5, wherein said testing act comprises testing said die while said die is part of a cellular telephone system.

7-63. (Canceled)